January 2001

# FDN304P P-Channel 1.8V Specified PowerTrench<sup>®</sup> MOSFET

# **General Description**

This P-Channel 1.8V specified MOSFET uses Fairchild's advanced low voltage PowerTrench process. It has been optimized for battery power management applications.

# Applications

- Battery management
- Load switch
- Battery protection

# Features

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• -2.4 A, -20 V. R_{DS(ON)} = 52 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}
R_{DS(ON)} = 70 \text{ m}\Omega @ V_{GS} = -2.5 \text{ V}
R_{DS(ON)} = 100 \text{ m}\Omega @ V_{GS} = -1.8 \text{ V}
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- Fast switching speed
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- SuperSOT<sup>TM</sup> -3 provides low R<sub>DS(ON)</sub> and 30% higher power handling capability than SOT23 in the same footprint

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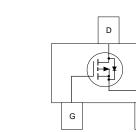


Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		±8	V
I <sub>D</sub>	Drain Current – Continuous	(Note 1a)	-2.4	A
	– Pulsed		-10	
PD	Maximum Power Dissipation	(Note 1a)	0.5	W
		(Note 1b)	0.46	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperatu	re Range	-55 to +150	°C
Therma	I Characteristics			
R <sub>0JA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	250	°C/W
	Thermal Resistance, Junction-to-Case	(Note 1)	75	°C/W

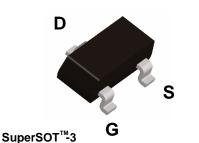
# Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
304 F	DN304P	7"	8mm	3000 units

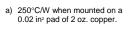
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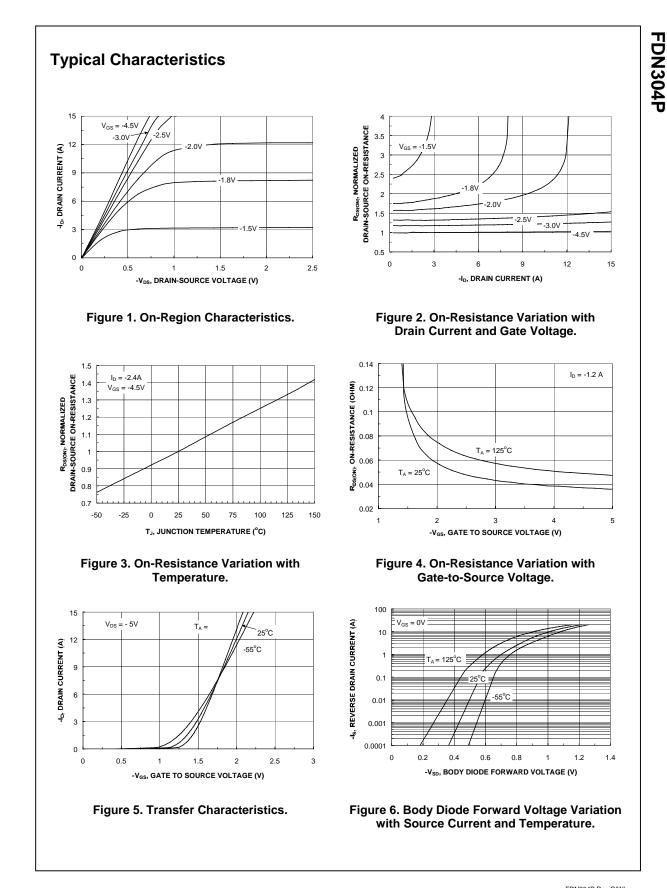


Off Char	Parameter	Test Conditions	Min	Тур	Max	Units
ULL GUALA	acteristics				1	
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 V, I_D = -250 \mu A$	-20			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		-13		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V},  V_{GS} = 0 \text{ V}$			-1	μA
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -8 V$ $V_{DS} = 0 V$			-100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	-0.4	-0.8	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}, \text{Referenced to } 25^\circ\text{C}$		3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V},  I_D = -2.4 \text{ A}$		36	52	mΩ
		$ \begin{array}{ll} V_{GS} = -2.5 \ V, & I_{D} = -2.0 \ A \\ V_{GS} = -1.8 \ V, & I_{D} = -1.8 \ A \end{array} $		47 65	70 100	
I <sub>D(on)</sub>	On–State Drain Current	$V_{GS} = -4.5 V$ , $V_{DS} = -5 V$	-10	00	100	А
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 V$ , $I_D = -1.25 A$		12		S
	Characteristics					Ū
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -10 V$ , $V_{GS} = 0 V$ ,		1312		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0  MHz		240		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			106		pF
	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = -10 V$ , $I_D = -1 A$ ,		15	27	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{GS} = -4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		15	27	ns
t <sub>i</sub> t <sub>d(off)</sub>	Turn–Off Delay Time	-		40	64	ns
t <sub>f</sub>	Turn–Off Fall Time	-		25	40	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = -10 \text{ V}, \qquad I_D = -2.4 \text{ A},$		12	20	nC
	Gate-Source Charge	$V_{GS} = -4.5 V$		2		nC
-			1	2		nC
Q <sub>gs</sub>	Gale-Dialit Charge			I		-
Q <sub>gs</sub> Q <sub>gd</sub>	Gate-Drain Charge	and Maximum Patings				
Q <sub>gs</sub> Q <sub>gd</sub>	Durce Diode Characteristics Maximum Continuous Drain–Source				-0.42	A

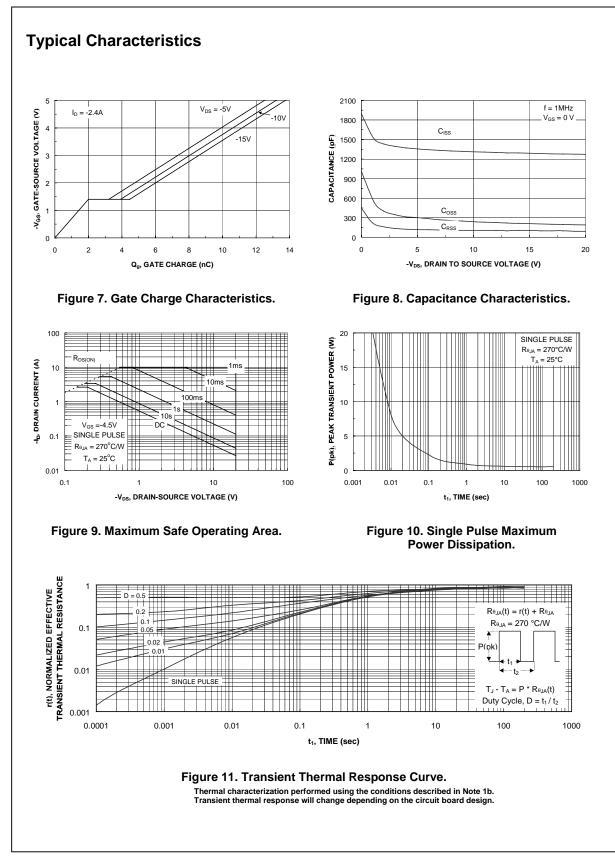


6 Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300 µs, Duty Cycle  $\leq$  2.0%



FDN304P Rev C(W)



FDN304P Rev C(W)

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